



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10777142</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>IDE ET AL.</p>
	<p>Examiner</p> <p>Al-Nazer, Leith A</p>	<p>Art Unit</p> <p>2821</p>


Class	SubClass	Date	Examiner
349	149-152	07/19/2006	Leith Al-Nazer
349	149-152	10/18/2006	Leith Al-Nazer

U.S. Patent and Trademark Office	Part of Paper No.: 20061018
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<i>Interference Searched</i> 	Application/Control No. 10777142	Applicant(s)/Patent Under Reexamination IDE ET AL.
	Examiner Al-Nazer, Leith A	Art Unit 2821

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Search Notes 	Application/Control No. 10777142	Applicant(s)/Patent Under Reexamination IDE ET AL.
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Notes	Date	Examiner
Updated EAST prior art text search (see "Examiner Search Notes")	07/19/2006	Leith Al-Nazer
Updated EAST prior art text search (see "Examiner Search Notes")	10/18/2006	Leith Al-Nazer
EAST interference text search (see "Examiner Search Notes")	10/18/2006	Leith Al-Nazer
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